

<b>Notice of References Cited</b>	Application/Control No. 10/533,059	Applicant(s)/Patent Under Reexamination WEGH ET AL.	
	Examiner Shean C. Wu	Art Unit 1756	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,597,856	07-2003	Van De Witte et al.	385/141
*	C	US-6,671,031	12-2003	Nishimura, Suzushi	349/201
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**NON-PATENT DOCUMENTS**

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